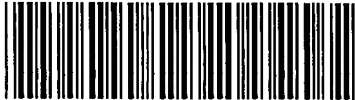


<b>Search Notes</b> 	<b>Application/Control No.</b> 10501315	<b>Applicant(s)/Patent Under Reexamination</b> TO, BAN CHIN
	<b>Examiner</b> Makiya, David J	<b>Art Unit</b> 2885

SEARCHED			
Class	Subclass	Date	Examiner
362	365	9/25/2007	DJM

SEARCH NOTES		
Search Notes	Date	Examiner
Search in EAST attached	9/25/2007	DJM
362/147,148,150	9/25/2007	DJM

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner